

Multi-Chip Module Status

MVD Critical Path

Electronic die fabrication and MCM define electronics schedule

All electronic die designed

AMUADC in fabrication

TGV32 -

Last minute switch to HP

Design review Dec 15 - results look good

Xilinx 4010 in fabrication

All must be Known Good Die - ISE

MCM high risk

Design impacts **ALL** of mechanics and cooling designs

Only one vendor! - Lockheed Martin

LDRD project on simpler MCM:

Used 8 channel die
32 total channels

8 months behind schedule

100% cost overrun

Poor communication and management

Little Q&A procedures

Low yield

Currently being tested

Meeting at Lockheed Martin - November 17th

- * Management reports to us once a week
- * Q&A procedures defined and monitored
- * Have recently unionized - rigid training
- * Changing from R&D to production facility
- * Have increased facility in terms of setup
- * Purchased equipment spares
- * Have prepared opening in schedule with little competition
- * Detailed SOW
- * LANL Designer at LM for design exchange and verification
- * Cost + fixed fee contract is risk

Tentatively and generally agreed to cost and schedule

Final MCM

Design at LANL/NIS

Lead Engineer - Gary Smith

Lead Designer - Gary Richardson

256 channels/MCM

4 preamp, 4 AMUADC, 2-4010, opamp, T
sensor per MCM

Trace pitch = 54 μm

line width = 43 μm

I/O pad pitch = 150 μm

4 layers + base metal

M0 = 0.1 μm titanium/0.3 μm Cu/4 μm Cu

M1 = Signals, all connections off IC chips

M2 = Bus lines

M3 = Power lines

M4 = surface mount components